


<b>Search Notes</b>  	<b>Application/Control No.</b>  10541028	<b>Applicant(s)/Patent Under Reexamination</b>  SUKENO ET AL.
	<b>Examiner</b>  DAVID H CHU	<b>Art Unit</b>  2628

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
EAST (US-PGBUB, USPAT, USOCR, EPO, IBM_TDB)	12/20/2008	DHC
EAST (text search only - see search history printout)	12/20/2008	DHC
(combined text search - see search history printout)	12/20/2008	DHC

INTERFERENCE SEARCH			
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	Interference search done - see search history printout	12/20/2008	DHC

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